

March 2013

FQP5N60C / FQPF5N60C N-Channel QFET MOSFET

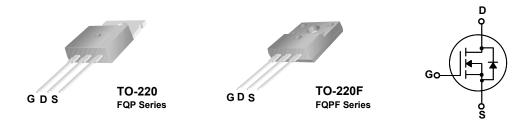
600 V, 4.5 A, 2.5 Ω

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- + 4.5 A, 600 V, $R_{DS(on)}$ = 2.5 Ω (Max) @V_{GS} = 10 V, I_D = 2.25 A
- Low Gate Charge (Typ. 15 nC)
- Low Crss (Typ. 6.5 pF)
- 100% Avalanche Tested



Absolute Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		FQP5N60C	FQPF5N60C	Units
V _{DSS}	Drain-Source Voltage		600		V
I _D	Drain Current - Continuous (T _C = 25°C)		4.5	4.5 *	Α
	- Continuous (T _C = 100°C)		2.6	2.6 *	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	18	18 *	Α
V_{GSS}	Gate-Source Voltage		± 30		V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	210		mJ
I _{AR}	Avalanche Current	(Note 1)	4.5		Α
E _{AR}	Repetitive Avalanche Energy (No		10		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns
P_D	Power Dissipation (T _C = 25°C)		100	33	W
	- Derate above 25°C		0.8	0.26	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C
T _L	Maximum lead temperature for soldering purposes,		300		°C
	1/8" from case for 5 seconds		000		

^{*} Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FQP5N60C	FQPF5N60C	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.25	3.79	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	600			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	1	0.6		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 480 V, T _C = 125°C	-		10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.25 A		2.0	2.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 2.25 A (Note 4)	-	4.7		S
Dynami C _{iss}	ic Characteristics Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		515	670	pF
C _{oss}	Output Capacitance	$\int_{0}^{\infty} \int_{0}^{\infty} \int_{0$		55	72	pF
C _{rss}	Reverse Transfer Capacitance	1		6.5	8.5	pF
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V 200 V I 454		10	30	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_{D} = 4.5\text{A},$ $R_{G} = 25 \Omega$		42	90	ns
t _{d(off)}	Turn-Off Delay Time	NG - 20 22		38	85	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		46	100	ns
Q _g	Total Gate Charge	V _{DS} = 480 V, I _D = 4.5A,		15	19	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		2.5		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		6.6		nC
	ource Diede Characteristics of	nd Maximum Patings				
I _S	Source Diode Characteristics and Maximum Ratings Maximum Continuous Drain-Source Diode Forward Current				4.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F				18	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 4.5 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 4.5 A,		300		ns

 $dI_F / dt = 100 A/\mu s$

(Note 4)

2.2

Q_{rr}

Reverse Recovery Charge

μС

Notes:
1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 18.9mH, I_{AS} = 4.5 A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ 4.5A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

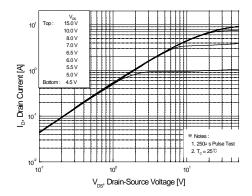


Figure 1. On-Region Characteristics

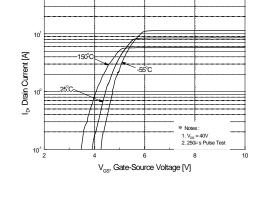


Figure 2. Transfer Characteristics

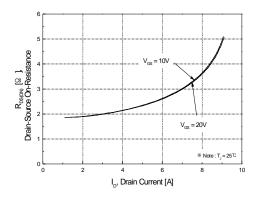


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

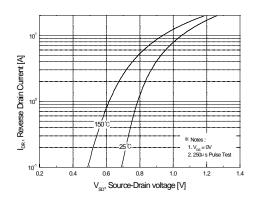


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

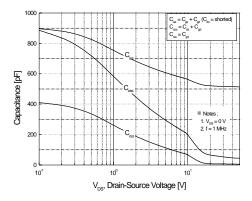


Figure 5. Capacitance Characteristics

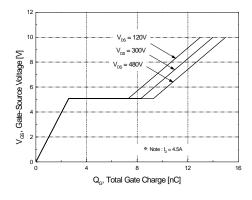


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

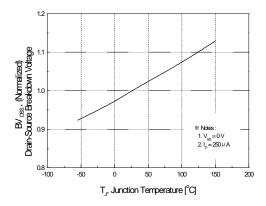


Figure 7. Breakdown Voltage Variation vs Temperature

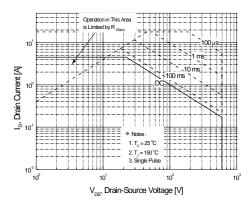


Figure 9-1. Maximum Safe Operating Area for FQP5N60C

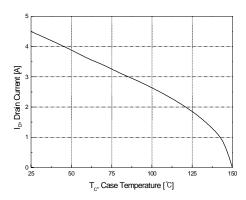


Figure 10. Maximum Drain Current vs Case Temperature

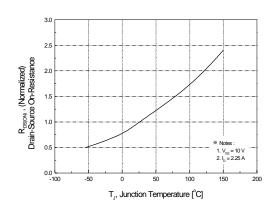


Figure 8. On-Resistance Variation vs Temperature

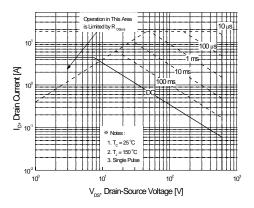


Figure 9-2. Maximum Safe Operating Area for FQPF5N60C

Typical Characteristics (Continued)

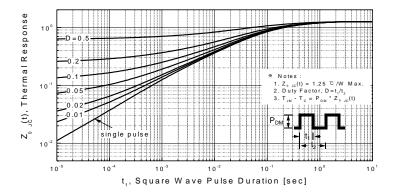


Figure 11-1. Transient Thermal Response Curve for FQP5N60C

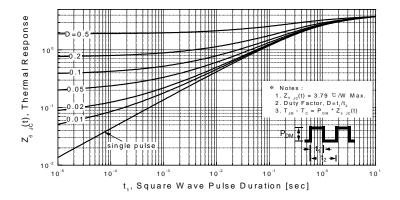
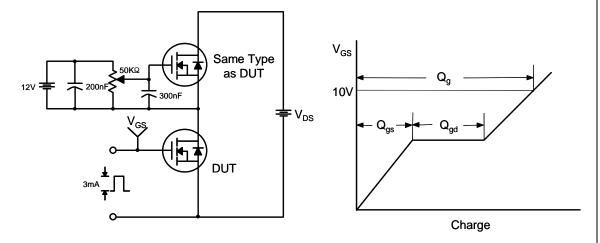


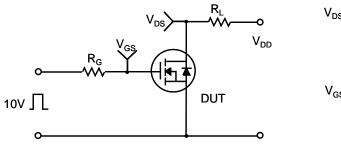
Figure 11-2. Transient Thermal Response Curve for FQPF5N60C

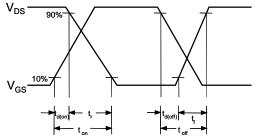
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Gate Charge Test Circuit & Waveform

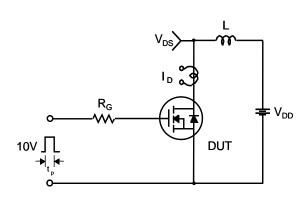


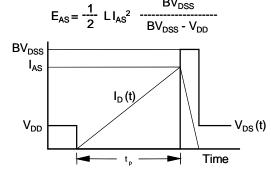
Resistive Switching Test Circuit & Waveforms



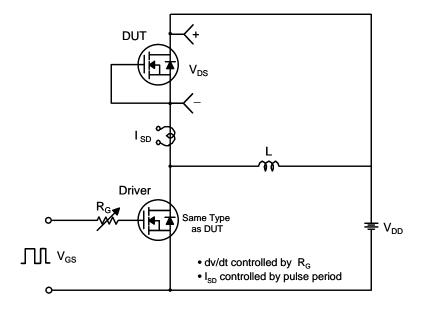


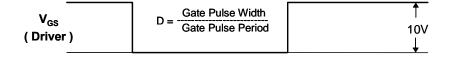
Unclamped Inductive Switching Test Circuit & Waveforms

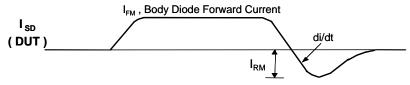




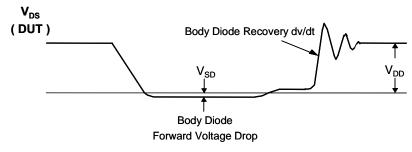
Peak Diode Recovery dv/dt Test Circuit & Waveforms







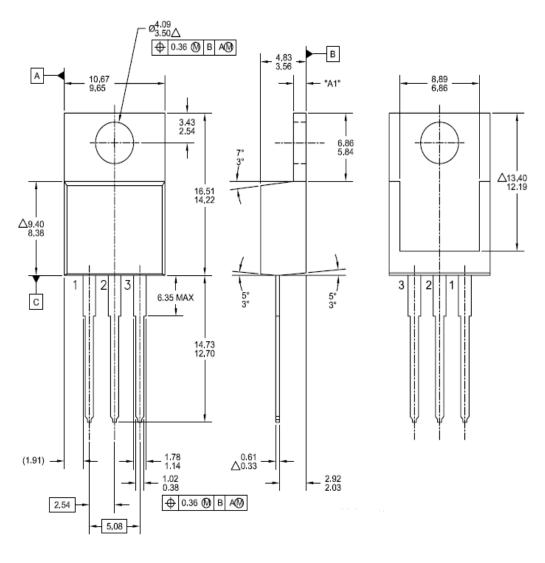
Body Diode Reverse Current

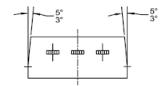


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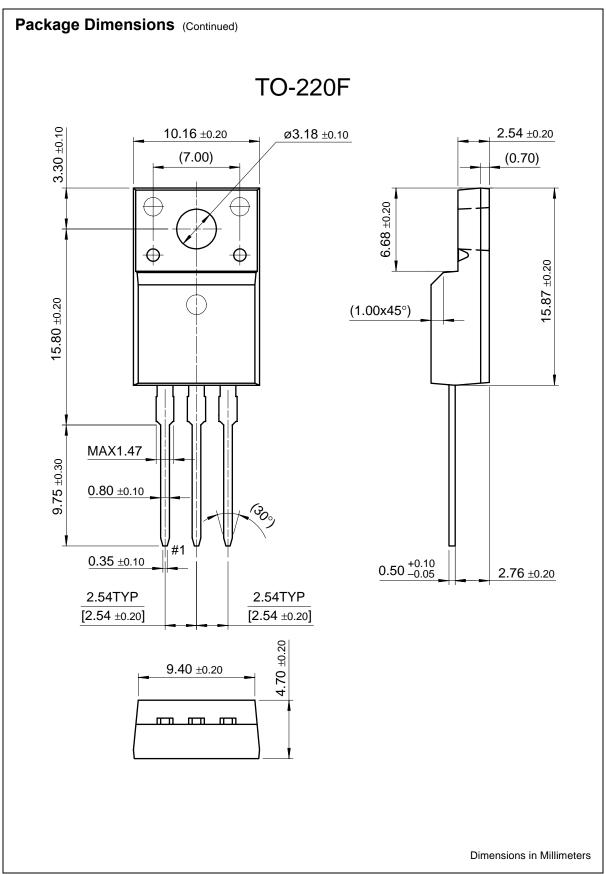
Mechanical Dimensions

TO - 220





Dimensions in Millimeters







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